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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Patrick P. Naulleau	
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U.S. PATENT DOCUMENTS

Examiner Initials	U.S. Patent Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)
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Examiner Initials	Foreign Patent Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translation Yes	Translation no
	NONE					

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
PL	Naulleau, P. et al., "Characterization of the accuracy of EUV phase-shifting point diffraction interferometry", *SPIE*, vol. 3331, pp. 114-123
PL	White, D.L. et al., "Modification of the coherence of undulator radiation", *Rev. Sci. Instrum.*, 66 (2), Feb. 1995, pp. 1930-1933

Examiner Signature	Amel C. Farais	Date Considered	10/18/02

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